inference technologies

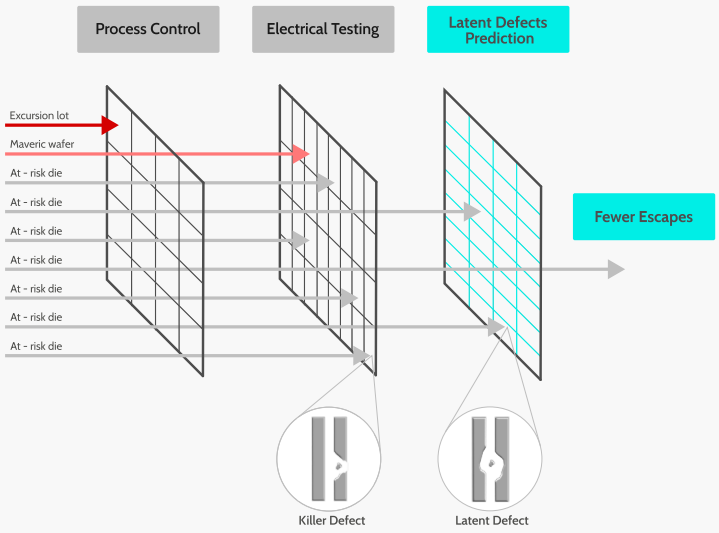
inSure

Smart Reliability Control

BENEFITS

- **Screening Latent Defects:** Ensures that dice with a high predicted failure probability, which have passed the Wafer Sort stage are filtered out.
- **Reliability improvement:** It provides an automated, cost-efficient method for downgrading the Wafer Sort map and/or implementing adaptive burn-in.
- **Balanced approach:** Achieving a balanced screening process that minimizes both unnecessary rejection of functional dice (overkill) and the risk of undetected defects (underkill).
- **Early Warning System:** Receive early alerts for process issues immediately after the defect inspection stage, enabling timely corrective actions.
- **Sustainable Manufacturing:** By identifying potential latent defects before assembly and customer delivery, you can reduce waste and align manufacturing with the principles of a circular economy.

MINIMIZE DEFECT ESCAPES



TECHNOLOGIES

- From raw files to model inference by employing self-hosted data pipeline.
- Machine learning model designed to optimize the cost and reability objective function.
- Data under control with model inference behind your firewall.

APPLICATIONS

- Screen out dice with potential reliability risk, featuring flexible integration into the Map Downgrade System.
- In-process yield prediction that provides valuable feedback for upstream process stages.
- SiC substrate and epitaxy quality monitoring with respect to yield and potential reliability risk.

MARKETS

- IDM
- Foundry
- Fabless

GET IN TOUCH

- contact@inferencetech.com
- +420 702 066 383